TOSHIBA CCD Linear Image Sensor CCD (Charge Coupled Device)

# TCD2725BFG



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The TCD2725BFG is a high sensitive and low dark current 7450 elements  $\times$  3 lines output CCD color linear image sensor.

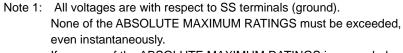
The device contains a row of 7450 elements  $\times$  3 lines photodiodes which provide 24 lines/mm across a A3 size paper. The device is operated by 3.3 V pulse and 10 V power supply.

#### **Features**

- Number of Image Sensing Elements: 7450 elements × 3 lines
- Image Sensing Element Size: 4.7 μm by 4.7 μm on 4.7 μm center
- Photo Sensing Region: High sensitive PN photodiode
- Clock: 2-phase (3.3 V)
- Power Supply Voltage: 10 V (typ.)
- Distance between Photodiode Array: 18.8 μm (4 lines) R array G array, G array B array
- Internal Circuit: Clamp circuit, Sample and hold circuit, Low input capacitance
- Package: 32 pin CLCC
- · Color Filter: Red, Green, Blue

## ABSOLUTE MAXIMUM RATINGS (Note 1)

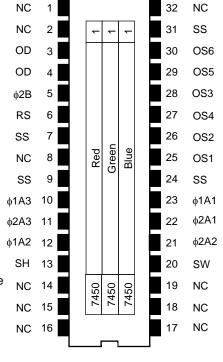
Characteristics	Symbol	Rating	Unit
Clock pulse voltage	$V_{\varphi A}$		
Last stage clock pulse voltage	V <sub>φ</sub> B		
Shift pulse voltage	VsH	-0.3 to +8.0	V
Reset pulse voltage	V <sub>RS</sub>		
Enable switch pulse voltage	VESW		
Power supply voltage	V <sub>OD</sub>	-0.3 to +13.5	V
Operating temperature	T <sub>opr</sub>	0 to 60	°C
Storage temperature	T <sub>stg</sub>	-25 to +85	°C



If any one of the ABSOLUTE MAXIMUM RATINGS is exceeded, the electrical characteristics, reliability and life time of the device cannot be guaranteed. If the ABSOLUTE MAXIMUM RATINGS are exceeded, the device can be permanently damaged or degraded. Create a system design in such a manner that any of the ABSOLUTE MAXIMUM RATINGS will not be exceeded under any circumstances.

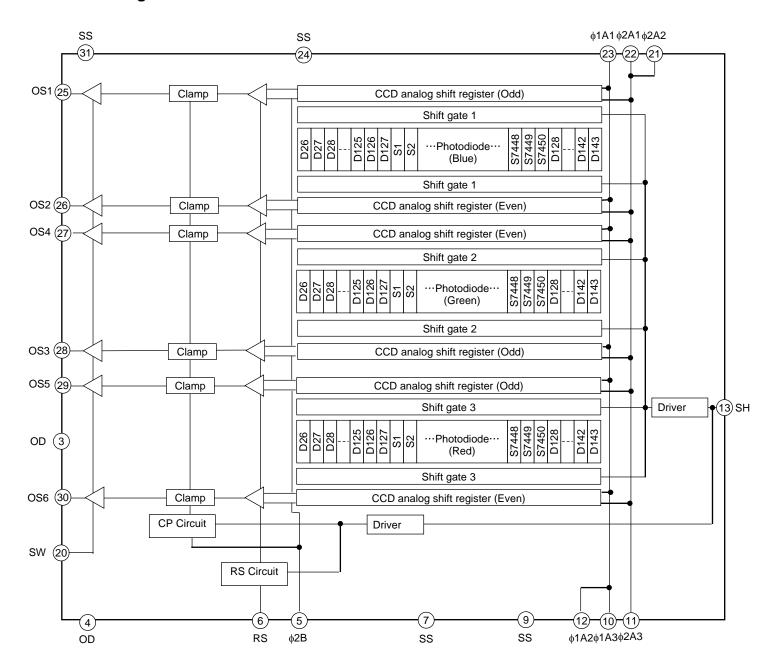


#### Pin Connections (top view)





## **Circuit Diagram**



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## **Pin Names**

Pin No.	Symbol	Name	Pin No.	Symbol	Name
1	NC	Non connection	32	NC	Non connection
2	NC	Non connection	31	SS	Ground
3	OD	Power supply	30	OS6	Output signal 6 (Red(Even))
4	OD	Power supply	29	OS5	Output signal 5 (Red(Odd))
5	ф2В	Last stage transfer clock (phase 2)	28	OS3	Output signal 3 (Green(Odd))
6	RS	Reset gate	27	OS4	Output signal 4 (Green(Even))
7	SS	Ground	26	OS2	Output signal 2 (Blue(Even))
8	NC	Non connection	25	OS1	Output signal 1 (Blue(Odd))
9	SS	Ground	24	SS	Ground
10	φ1A3	Transfer clock 3 (phase 1)	23	φ1A1	Transfer clock 1 (phase 1)
11	ф2А3	Transfer clock 3 (phase 2)	22	φ2A1	Transfer clock 1 (phase 2)
12	φ1A2	Transfer clock 2 (phase 1)	21	φ2A2	Transfer clock 2 (phase 2)
13	SH	Shift gate	20	SW	Switch gate (Sample and hold output select)
14	NC	Non connection	19	NC	Non connection
15	NC	Non connection	18	NC	Non connection
16	NC	Non connection	17	NC	Non connection

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#### **Optical/Electrical Characteristics**

Ta = 25°C, VoD = 10 V,  $V_{\phi}$  = VRS = VSH = 3.3 V (pulse),  $f_{\phi}$  = 1.0 MHz, tint (integration time) = 10 ms, light source = A light source + CM500S (t = 1.0 mm)

Characteristics		Symbol	Min	Тур.	Max	Unit	Note
	Red	R <sub>R</sub>	9.0	12.8	16.6		
Sensitivity	Green	RG	8.3	11.9	15.4		
Enable sample and hold	Blue	R <sub>B</sub>	3.6	5.2	6.8	\//li	(1) ( 0)
On and the state of	Red	R <sub>R</sub>	10.0	14.3	18.6	V/lx⋅s	(Note 2)
Sensitivity	Green	RG	9.3	13.4	17.4		
Disable sample and hold	Blue	R <sub>B</sub>	4.0	5.8	7.5		
Photo response non uniformity		PRNU (1)	_	5	20	%	(Note 3)
		PRNU (3)	_	3	12	mV	(Note 4)
Saturation output voltage		Vsat	1.2	1.8	_	V	(Note 5)
Saturation exposure		SE	0.07	0.13	_	lx⋅s	(Note 6)
Dark signal voltage		VDRK	_	0.5	6	mV	(Note 7)
Dark signal non uniformity		DSNU	_	10	12	mV	(Note 8)
DC power dissipation		PD	_	700	1050	mW	_
Total transfer efficiency		TTE	92	97		%	_
Output impedance		ZO	_	0.2	0.5	kΩ	_
DC output signal voltage		Vos	3.7	5.2	6.7	V	(Note 9)
Random noise (Enable sample and hold)		N <sub>Dσ</sub>	_	1.4	_	>/	(N-1-40)
Random noise (Disable sample and hold)			_	1.1	_	mV	(Note 10)

Note 2: Sensitivity is defined for each color of signal outputs average when the photosensitive surface is applied with the light of uniform illumination and uniform color temperature.

Note 3: PRNU (1) is defined for each color on a single chip by the expressions below when the photosensitive surface is applied with the light of uniform illumination and uniform color temperature, where measured approximately 570 mV of signal output.

$$PRNU(1) = \frac{\Delta X}{\overline{X}} \times 100 \, (\%)$$

X : Average of total signal outputs

 $\Delta X$ : The maximum deviation from  $\overline{X}$ 

Note 4: PRNU (3) is defined as the maximum voltage with next pixel, where measured approximately 50 mV of signal output.

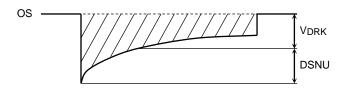
Note 5: VSAT is defined as the minimum saturation output voltage of all effective pixels.

Note 6: Definition of SE:

$$SE = \frac{V_{SAT}}{R_G}$$

Note 7: VDRK is defined as average dark signal voltage of all effective pixels.

Note 8: DSNU is defined by the difference between average value (VDRK) and the maximum value of the dark voltage.

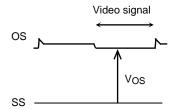




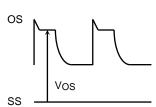
Note 9: DC output signal voltage is defined as follows.

Video signal with sample and hold represents the dummy outputs period.

#### Enable sample and hold



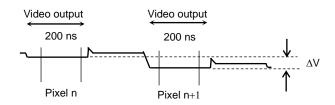
#### Disable sample and hold



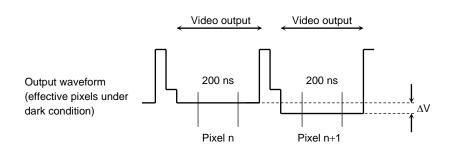
Note 10: Random noise is defined as the standard deviation (sigma) of the output level difference between two adjacent effective pixels under no illumination (i.e. dark condition) calculated by the following procedure.

#### Enable sample and hold

Output waveform (effective pixels under dark condition)



#### Disable sample and hold



- 1) Two adjacent pixels (pixel n and n+1) in one reading are fixed as measurement points.
- 2) Each of the output levels at video output periods averaged over 200 ns period to get V(n) and V(n+1).
- 3) V(n+1) is subtracted from V(n) to get  $\Delta V$ .

$$\Delta V = V(n) - V(n{+}1)$$

4) The standard deviation of  $\Delta V$  is calculated after procedure 2) and 3) are repeated 30 times (30 readings).

$$\overline{\Delta V} = \frac{1}{30} \sum_{i=1}^{30} \!\! \left| \Delta Vi \right| \qquad \qquad \sigma = \sqrt{\frac{1}{30} \sum_{i=1}^{30} \!\! \left( \!\! \left| \Delta Vi \right| - \overline{\Delta V} \right)^{\!2}}$$

- 5) Procedure 2), 3) and 4) are repeated 10 times to get sigma value.
- 6) 10 sigma values are averaged.

$$\overline{\sigma} = \frac{1}{10} \sum_{j=1}^{10} \sigma_j$$

7)  $\bar{\sigma}$  value calculated using the above procedure is observed  $\sqrt{2}$  times larger than that measured relative to the ground level. So we specify the random noise as follows.

$$ND_{\sigma} = \frac{1}{\sqrt{2}}\bar{\sigma}$$



## **Recommended Operating Conditions (Ta = 25°C)**

For best performance, the device should be used within the Recommended Operating Conditions.

Characteristics		Symbol	Min	Тур.	Max	Unit
Clock pulse velters	"H" level	V <sub><math>\phi</math>1A</sub>	3.1	3.3	5.5	V
Clock pulse voltage	"L" level	V <sub>ф2A</sub>	0	0	0.1	
Last stage clock pulse	"H" level	Vian	3.1	3.3	5.5	V
voltage	"L" level	V <sub>ф2B</sub>	0	0	0.1	
Shift pulse voltage	"H" level	Vau	3.1	3.3	5.5	V
	"L" level	VsH	0	0	0.1	
Poset pulse voltage	"H" level	Vpo	3.1	3.3	5.5	V
Reset pulse voltage	"L" level	V <sub>RS</sub>	0	0	0.1	V
Enable switch pulse	"H" level	\/	3.1	3.3	5.5	V
voltage	"L" level	VESW	0	0	0.1	V
Power supply voltage		V <sub>OD</sub>	9.5	10.0	10.5	V

## Clock Characteristics (Ta = 25°C)

For best performance, the device should be used within the Recommended Operating Conditions.

Characteristics	Symbol	Min	Тур.	Max	Unit
Clock pulse frequency	fφ	1.0	1.0	35.0	MHz
Reset pulse frequency	fRS	RS 1.0		35.0	MHz
Clock capacitance (Note 11)	СфА	_	65	_	pF
Last stage clock capacitance	СфВ	_	7	_	pF
Shift gate capacitance	CsH	_	20	_	pF
Reset gate capacitance	CRS	_	7		pF

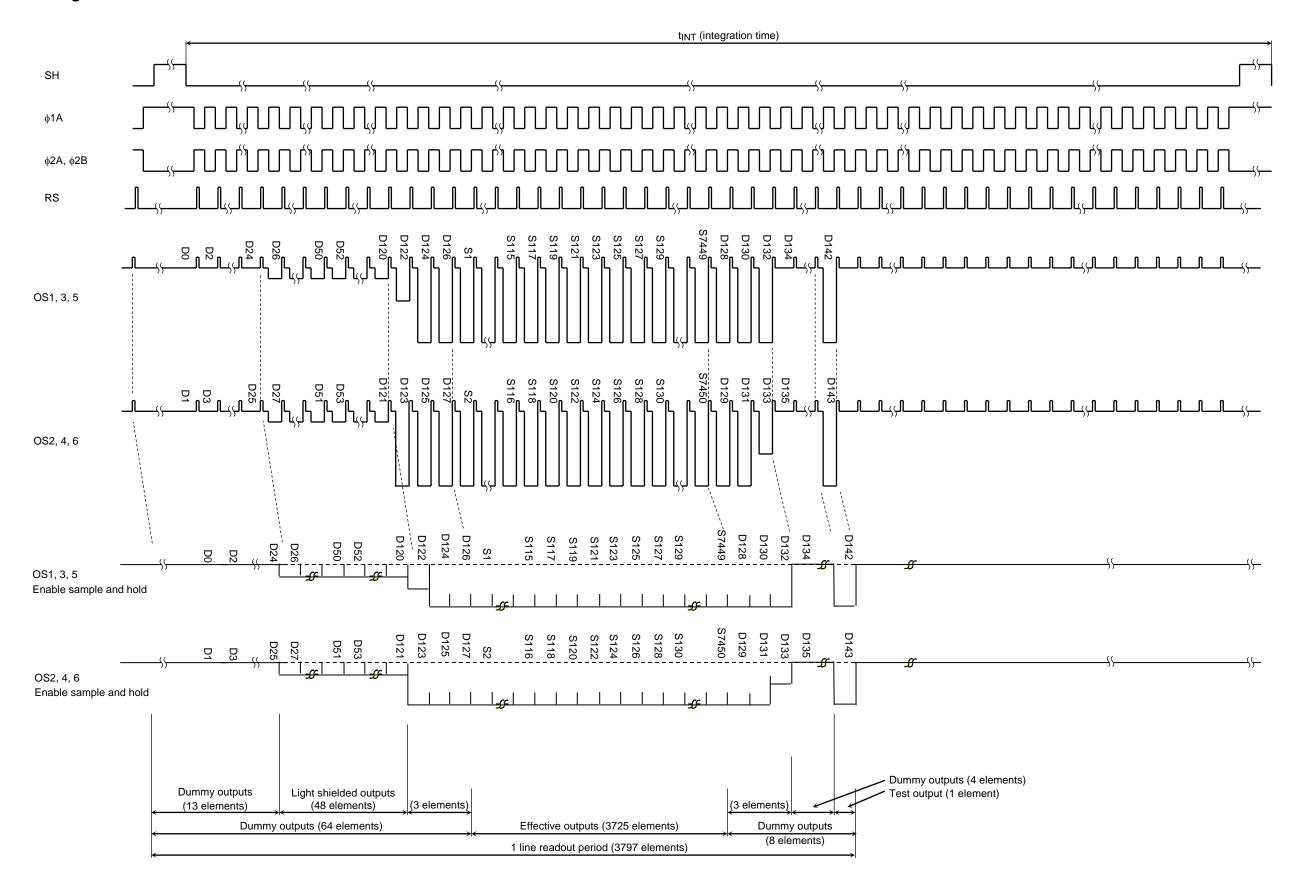
Note 11: VOD = 10 V, Input capacitance per a pin.

## **Mode Select (Selection Sample and Hold)**

Mode	SW
Enable sample and hold	"H"
Disable sample and hold	"L"



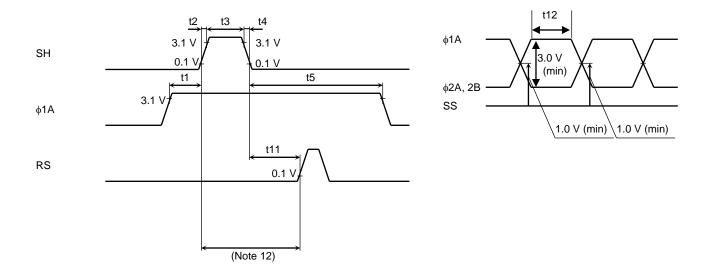
## **Timing Chart 1**



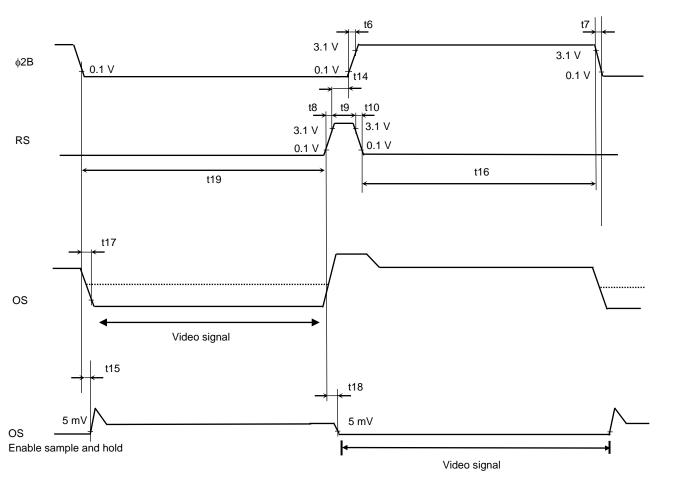
Rev.2.3 2019-01-15



## **Timing Requirements**



Note 12: Keep the RS pin "L" level.



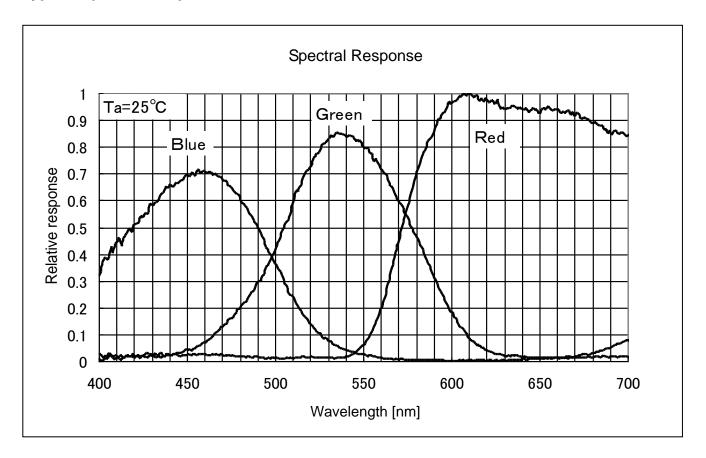


Characteristics	Symbol	Min	Typ. (Note 13)	Max	Unit
Dulga timing of CH and 14.0	t1	120	1000	_	ns
Pulse timing of SH and φ1A	t5	1000	1200	_	ns
SH pulse rise time, fall time	t2, t4	0	50	_	ns
SH pulse width	t3	2000	5000	_	ns
φ2B pulse rise time, fall time	t6, t7	0	50	_	ns
RS pulse rise time, fall time	t8, t10	0	20	_	ns
RS pulse width	t9	6	100	_	ns
Pulse timing of SH and RS	t11	500	_	_	ns
φ1A, φ2A pulse width	t12	7	100	_	ns
	t14	0	0	_	ns
Pulse timing of φ2B and RS	t16	6	100	_	ns
	t19	8	100	_	ns
Video data delay time	t17	_	7	_	ns
Video data delay time	t18		7		20
Enable sample and hold	110			_	ns
φ2B pulse timing of OS	t15	_	0	_	ns

Note 13: Measured with fRS = 1 MHz.



## **Typical Spectral Response**





#### **Cautions**

#### 1. Electrostatic Breakdown

Store in shorting clip or in conductive foam to avoid electrostatic breakdown.

CCD Image Sensor is protected against static electricity, but inferior puncture mode device due to static electricity is sometimes detected. In handing the device, it is necessary to execute the following static electricity preventive measures, in order to prevent the trouble rate increase of the manufacturing system due to static electricity.

- a. Prevent the generation of static electricity due to friction by making the work with bare hands or by putting on cotton gloves and non-charging working clothes.
- b. Discharge the static electricity by providing earth plate or earth wire on the floor, door or stand of the work room.
- c. Ground the tools such as soldering iron, radio cutting pliers of or pincer.
- d. Ionized air is recommended for discharge when handling CCD image sensors.

It is not necessarily required to execute all precaution items for static electricity.

It is all right to mitigate the precautions by confirming that the trouble rate within the prescribed range.

#### 2. Incident Light

CCD sensor is sensitive to infrared light. Note that infrared light component degrades resolution and PRNU of CCD sensor.

#### 3. Cloudiness of Glass Inside

CCD surface mount products may have a haze on the inside of glass, so be careful about following. Even if the haze arises inside of glass, when it is not on the pixel area, there is no problem in quality. Before the aluminum bag is opened, please keep the products in the environment below 30°C·90 %RH. And after the aluminum bag is opened, please keep the products in the environment below 30°C·60 %RH. Please mount the products within 12 months from sealed date and within 6 months from opening the aluminum bag. (Sealed date is printed on aluminum bag.)

#### 4. Ultrasonic Cleaning

Ultrasonic cleaning should not be used with such hermetically-sealed ceramic package as CCD because the bonding wires can become disconnected due to resonance during the cleaning process.

#### 5. Mounting

In the case of solder mounting, the devices should be mounted with the window glass protective tape in order to avoid dust or dirt included in reflow machine.

#### 6. Window Glass Protective Tape

The window glass protective tape is manufactured from materials in which static charges tend to build up. When removing the tape from CCD sensor after solder mounting, install an ionizer to prevent the tape from being charged with static electricity.

When the tape is removed, adhesives will remain in the glass surface. Since these adhesives appear as black or white flaws on the image, please wipe the window glass surface with the cloth into which the organic solvent was infiltrated. Then please attach CCD to a product.

Do not reuse the tape.



#### 7. Soldering Temperature Profile

Good temperature profile for each soldering method is as follows. In addition, in case of the repair work accompanied by IC removal, since the degree of parallel may be spoiled with the left solder, please do not carry out and in case of the repair work not accompanied by IC removal, carry out with a soldering iron or , in reflow, only one time.

- a. Using a soldering iron
  - Complete soldering within three seconds for lead temperatures of up to 350°C.
- b. Using long infrared rays reflow / hot air reflow

Please do reflow at the condition that the package surface (electrode) temperature is on the solder maker's recommendation profile. And that reflow profile is within below condition 1 to 3.

- 1. Peak temperature: 250°C or less.
- 2. Time to keep high temperature: 220 to 250°C, 30 to 40 s.
- 3. Pre. heat: 150 to 190°C, 60 to 120 s

#### 8. Window Glass

The dust and stain on the glass window of the package degrade optical performance of CCD sensor. Keep the glass window clean by saturating a cotton swab in alcohol and lightly wiping the surface, and allow the glass to dry, by blowing with filtered dry N2. Care should be taken to avoid mechanical or thermal shock because

the glass window is easily to damage.

#### 9. Cleaning Method of the Window Glass Surface

Wiping Cloth

- a. Use soft cloth with a fine mesh.
- b. The wiping cloth must not cause dust from itself.
- Use a clean wiping cloth necessarily.

#### Cleaner

When using solvents, such as alcohol, unavoidably, it is cautious of the next.

- a. A clean thing with quick-drying.
- b. After liquid dries, there needs to be no residual substance.
- c. A thing safe for a human body.

And, please observe the use term of a solvent and use the storage container of a solvent to be clean. Be cautious of fire enough.

#### Way of Cleaning

First, the surface of window glass is wiped with the wiping cloth into which the cleaner was infiltrated. Please wipe down the surface of window glass at least 2 times or more.

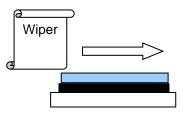
Next, the surface of window glass wipes with the dry wiping cloth. Please wipe down the surface of window glass at least 3 times or more.

Finally, blow cleaning is performed by dry N<sub>2</sub> filtered.

If operator wipes the surface of the window glass with the above-mentioned process and dirt still remains, TOSHIBA recommends repeating the clean operation from the beginning.

Be cautious of the next thing.

- a. Don't infiltrate the cleaner too much.
- b. A wiping portion is performed into the optical range and don't touch the edge of window glass.
- c. Be sure to wipe in a long direction and the same direction.
- A wiping cloth always uses an unused portion.

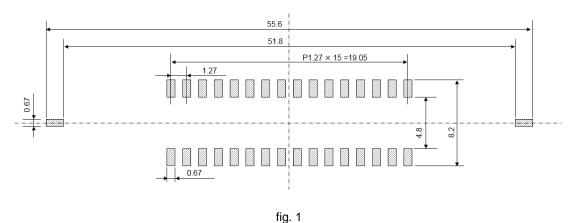




#### 10. Foot Pattern on the PCB

We recommend fig.1 's foot pattern for your PCB(Printed Circuit Board).

Unit: mm



#### 11. Mask for Solder Paste Application

We recommend metal mask that have the following thickness.

·Thickness: 0.2 mm.

And we recommend that the opened area size on the metal mask is 95 % to 100 % for pads on solder.

#### 12. Temperature Cycle

After mounting, if temperature cycle stress is too much, CCD surface mount products have a possibility that a crack may arise in solder. As a method of preventing a solder crack, underfill is effective.

#### 13. Reuse of a Tray

We reuse tray in order to reduce plastic waste as we can. Please cooperate with us in reusing for ecology.



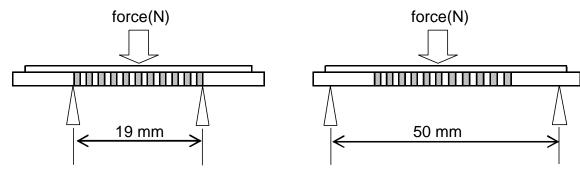
#### 14. Caution for Package Handling

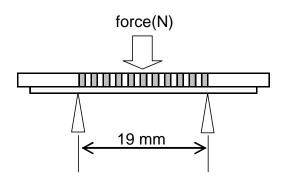
Over force on CCD products may cause crack and chip removing on the product. The three point bending strength of this product is the following. (Reference data)

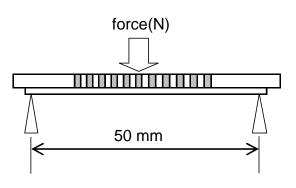
If the stress is loaded far from a fulcrum, the stress on the package will be increase.

When you will treat CCD on every process, please be careful particularly. For example, soldering on PCB, cutting PCB, wiping on the glass surface, optical assemble and so on.

### **Bending Test**







#### •32CLCC

Bearing length 19 mm: The force from upside: 250 [N]

The force from downside: 150 [N]

Bearing length 50 mm: The force from upside: 120 [N]

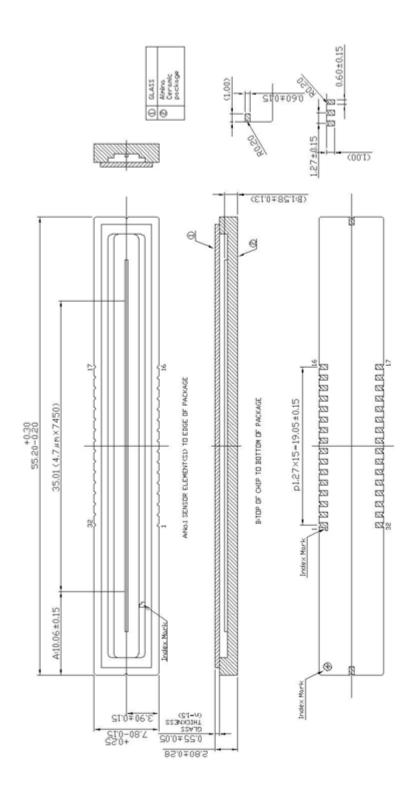
The force from downside: 60 [N]



## **Package Dimensions**

WQFN32-C-R300-1.27

Unit: mm





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